Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/005,936	MASUYAMA ET AL.
Examiner	Art Unit

Tse Chen

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Class	Subclass	Date	Examiner			
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Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Consulted J. Trujillo on interpretation of optional claim language	4/5/2007	TC
Inventor name	5/7/2007	тс
713/330 with "server address"	5/7/2007	TC
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